捷多邦,专业PCB打样工厂,24小时加急**SI&74LVC841A** 10-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS

SCAS307H - MARCH 1993 - REVISED AUGUST 1998

- **EPIC™** (Enhanced-Performance Implanted **CMOS) Submicron Process**
- Typical V_{OLP} (Output Ground Bounce) $< 0.8 \text{ V at V}_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- Typical V_{OHV} (Output V_{OH} Undershoot) $> 2 \text{ V at V}_{CC} = 3.3 \text{ V}, T_{A} = 25^{\circ}\text{C}$
- **Power Off Disables Outputs, Permitting** Live Insertion
- **Supports Mixed-Mode Signal Operation on** All Ports (5-V Input/Output Voltage With 3.3-V V_{CC})
- **ESD Protection Exceeds 2000 V Per** MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- **Package Options Include Plastic** Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) WWW.DZSC.COM **Packages**

DB,	DW,	OR	PW	PACKAGE
	(TOF	VIE	W)

OE [1	U	24	Vcc
1D [2		23] 1Q
2D [3		22] 2Q
3D [4		21] 3Q
4D [5		20] 4Q
5D [6		19] 5Q
6D [7		18] 6Q
7D [8		17] 7Q
8D [9		16] 8Q
9D [10		15] 9Q
10D 🛚	11		14] 10Q
I DNE	12		13	LE

description

This 10-bit bus-interface D-type latch is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74LVC841A is designed specifically for driving highly capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The ten latches are transparent D-type latches. The device has noninverting data (D) inputs and provides true data at its outputs.

A buffered output-enable (OE) input can be used to place the ten outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operations of the latch. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

To ensure the high-impedance state during power up or power down, OE should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVC841A is characterized for operation from -40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

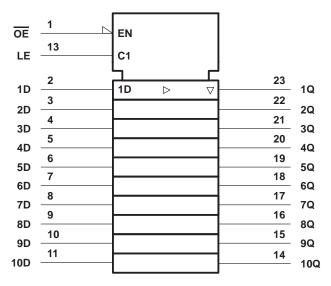
is a trademark of Texas Instruments Incorporated



FUNCTION TABLE

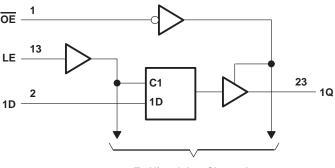
	INPUTS	OUTPUT	
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q ₀
Н	Χ	Χ	Z

logic symbol†



 $[\]ensuremath{^{\dagger}}$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Nine Other Channels



SN74LVC841A 10-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS

SCAS307H - MARCH 1993 - REVISED AUGUST 1998

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	–0.5 V to 6.5 V
Input voltage range, V _I (see Note 1)	0.5 V to 6.5 V
Voltage range applied to any output in the high-impedance or power-off state, VO	
(see Note 1)	0.5 V to 6.5 V
Voltage range applied to any output in the high or low state, VO	
(see Notes 1 and 2)	–0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Continuous output current, IO	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3): DB package	104°C/W
DW package	81°C/W
PW package	120°C/W
Storage temperature range, T _{stq}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The value of V_{CC} is provided in the recommended operating conditions table.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT		
\/00	Supply voltage	Operating	1.65	3.6	V		
VCC	Low-level input voltage Low-level input voltage Input voltage Output voltage High-level output current Low-level output current	Data retention only	1.5		V		
		V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}				
V_{IH}	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V		
	High-level input voltage Low-level input voltage Input voltage Output voltage High-level output current Low-level output current	V _{CC} = 2.7 V to 3.6 V	2				
		V _{CC} = 1.65 V to 1.95 V		0.35 × V _{CC}			
V_{IL}	Low-level input voltage	V _{CC} = 2.3 V to 2.7 V		0.7	V		
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8			
٧ı	Input voltage		0	5.5	V		
٧o	Output voltage	High or low state	0	Vcc	٧		
	Output voltage	3 state	0	5.5			
		V _{CC} = 1.65 V		-4			
la	High level output ourrent	V _{CC} = 2.3 V		-8	mA		
IOH	nigh-level output current	V _{CC} = 2.7 V		-12	IIIA		
	IL Low-level input voltage I Input voltage O Output voltage OH High-level output current OL Low-level output current	V _{CC} = 3 V		-24			
		V _{CC} = 1.65 V		4			
la.	Lour lovel output output	V _{CC} = 2.3 V		8	A		
IOL	Low-level output current	V _{CC} = 2.7 V		12	mA		
		V _{CC} = 3 V		24			
Δt/Δν	Input transition rise or fall rate		0	10	ns/V		
TA	Operating free-air temperature		-40	85	°C		

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



SN74LVC841A 10-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS

SCAS307H - MARCH 1993 - REVISED AUGUST 1998

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	ONDITIONS	Vcc	MIN	TYP [†]	MAX	UNIT
	I _{OH} = -100 μA		1.65 V to 3.6 V	V _{CC} -0.2			
	I _{OH} = -8 mA		2.3 V	1.7			V
	12 mΔ		2.7 V	2.2			V
	10H = -12 IIIA		3 V	2.4			
	I _{OH} = -24 mA		3 V	2.2			
	I _{OL} = 100 μA		1.65 V to 3.6 V			0.2	
VOL II Ioff IOZ ICC ΔICC Ci	I _{OL} = 4 mA	1.65 V			0.45	V	
	I _{OL} = 8 mA	2.3 V			0.7		
	I _{OL} = 12 mA		2.7 V			0.4	
	I _{OL} = 24 mA		3 V			0.55	
lį	V _I = 0 to 5.5 V		3.6 V			±5	μΑ
loff	V _I or V _O = 5.5 V		0			±10	μΑ
loz	V _O = 0 to 5.5 V		3.6 V			±10	μΑ
	$V_I = V_{CC}$ or GND					10	^
l cc	$3.6 \text{ V} \le \text{V}_{\text{I}} \le 5.5 \text{ V}^{\ddagger}$	10 = 0	3.6 V		-	10	μΑ
ΔlCC	One input at V _{CC} – 0.6 V,	Other inputs at V _{CC} or GND	2.7 V to 3.6 V			500	μΑ
Ci	$V_I = V_{CC}$ or GND		3.3 V		5		pF
Co	$V_O = V_{CC}$ or GND		3.3 V		7		pF

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _W	Pulse duration	§		§		3.3		3.3		ns
t _{su}	Setup time, data before LE↓	§		§		2.1		2.1		ns
th	Hold time, data after LE \downarrow	§		§		1		1		ns

[§] This information was not available at the time of publication.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.2 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
	(001701)	(001F01)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
	D	0	§	§	§	§		7.5	2.4	6.7	no
^t pd	LE	Q	§	§	§	§		8.6	2.7	7.6	ns
t _{en}	ŌĒ	Q	§	§	§	§		8.5	1.3	7.2	ns
^t dis	ŌĒ	Q	§	§	§	§		6.6	1.9	5.9	ns
t _{sk(o)} ¶										1	ns

[§] This information was not available at the time of publication.

 $[\]P$ Skew between any two outputs of the same package switching in the same direction



[‡] This applies in the disabled state only.

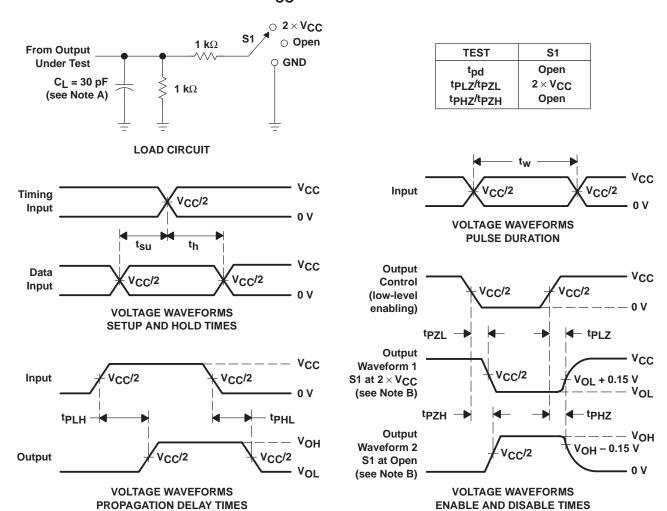
SN74LVC841A 10-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS SCAS307H - MARCH 1993 - REVISED AUGUST 1998

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V	UNIT	
				TYP	TYP	TYP	1
C _{pd}	Power dissipation capacitance	Outputs enabled	f = 10 MHz	†	†	25	pF
Popa	per latch	Outputs disabled	1 = 10 MH2	†	†	6	рг

[†]This information was not available at the time of publication.

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$

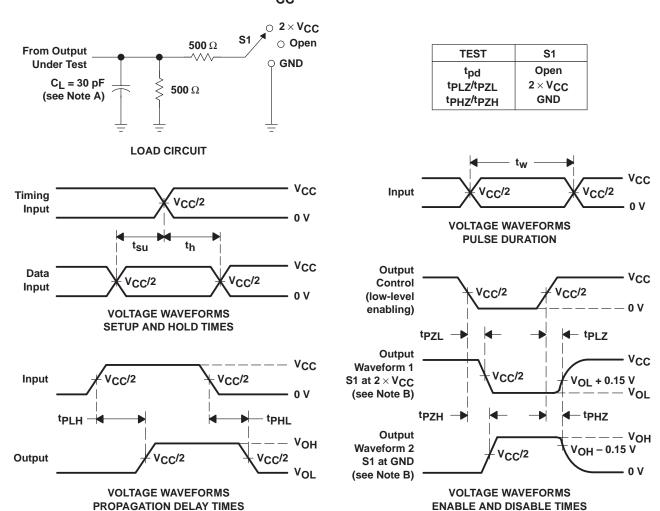


- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{Ω} = 50 Ω , $t_r \leq$ 2 ns, $t_f \leq$ 2 ns.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. tpLZ and tpHZ are the same as tdis.
 - F. tpZL and tpZH are the same as ten.
 - G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 V \pm 0.2 V$



NOTES: A. C_L includes probe and jig capacitance.

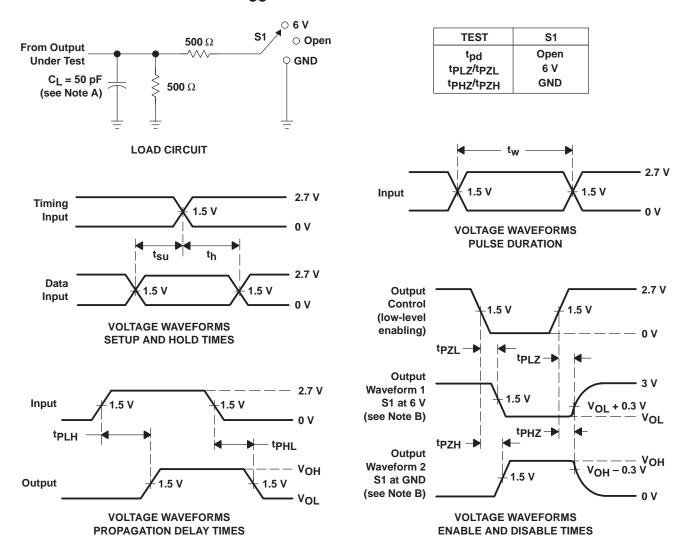
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50~\Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



SCAS307H - MARCH 1993 - REVISED AUGUST 1998

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.7 \text{ V}$ AND 3.3 V \pm 0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. t_{PZL} and t_{PZH} are the same as t_{en}.
- G. tplH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated